

Product Name: Smart Phone	Report No: ITEZA2-202400192RF7
Product Model: S118, V31, V31 GT, S110, S110 GT, V31 Plus, V31 Ultra, S118 Pro, S118 S, S118 E, S118 SE, S118 Plus, S118 Max, S118 Ultra	Security Classification: Open
Version: V1.0	Total Page: 57

TIRT Testing Report

Prepared By:	Checked By:	Approved By:	chnology See
Aaron Long	Stone Tang	Joky Wang	A TRT
Amon long	Stone Tang	Jopy Wany	HL shenzhen



RF TEST REPORT

FCC ID: 2AX4YS118

According to

FCC CFR Title 47 Part 2 FCC CFR Title 47 Part 22 Subpart H FCC CFR Title 47 Part 24 Subpart E FCC CFR Title 47 Part 27 Subpart C FCC CFR Title 47 Part 90 Subpart S ANSI C63.26:2015 KDB 971168 D01 Power Meas License Digital Systems v03r01

Applicant:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No.
Address.	22, Longhua New District, Shenzhen, China
Manufacturer:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No.
Address.	22, Longhua New District, Shenzhen, China
Sample No:	1000036597
Product Name:	Smart Phone
Brand Name:	DOOGEE
Model No.:	S118, V31, V31 GT, S110, S110 GT, V31 Plus, V31 Ultra, S118 Pro,
WOdel NO	S118 S, S118 E, S118 SE, S118 Plus, S118 Max, S118 Ultra
Test No.:	S118

Date of Receipt:	2024/06/13
Date of Test:	2024/06/13~2024/06/25
Issued Date:	2024/06/30
Testing Lab:	TIRT

Note: This report shall not be reproduced except in full, without the written approval of Beijing TIRT Technology Service Co.,Ltd Shenzhen.Laboratory.

This document may be altered or revised by Beijing TIRT Technology Service Co.,Ltd Shenzhen. Laboratory.Personnel only, and shall be noted in the revision section of the document. The test results of this report relate only to the tested sample identified in this report.

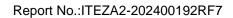




TABLE	OF	CONT	ENTS
-------	----	------	------

De	escri	otion	Page
1	TE	ST SUMMARY	5
2	GE	NERAL INFORMATION	7
	2.1	GENERAL DESCRIPTION OF EUT	7
	2.2	RELATED SUBMITTAL(S) / GRANT (S)	8
	2.3	TEST FACILITY	8
	2.4	ACCESSORIES OF DEVICE (EUT)	8
	2.5	TESTED SUPPORTING SYSTEM DETAILS	8
	2.6	TEST CONDITIONS	8
	2.7	MEASUREMENT UNCERTAINTY	9
3	TES	ST INSTRUMENTS LIST	10
4	SYS	STEM TEST CONFIGURATION	11
	4.1	TEST MODE	11
	4.2	CONFIGURATION OF TESTED SYSTEM	11
	4.3	CONDUCTED OUTPUT POWER	12
	4.4	PEAK-TO-AVERAGE RATIO	13
	4.5	OCCUPY BANDWIDTH	14
	4.6	MODULATION CHARACTERISTIC	15
	4.7	OUT OF BAND EMISSION AT ANTENNA TERMINALS	16
	4.8	ERP, EIRP MEASUREMENT	17
	4.9	FIELD STRENGTH OF SPURIOUS RADIATION MEASUREMENT	19
	4.10	FREQUENCY STABILITY V.S. TEMPERATURE MEASUREMENT	43
	4.11	FREQUENCY STABILITY V.S. VOLTAGE MEASUREMENT	44
	4.12	2 TEST SETUP PHOTO	45



History of this test report Original Report Issue Date: 2024.06.30

• No additional attachment

 \circ Additional attachments were issued following record

Attachment No.	Issue Date	Description



1 TEST SUMMARY		
Test Item	Section in CFR 47	Result
	Part 1.1307	Pass*(Please refer to
RF Exposure (SAR)	Part 2.1093	SAR Report)
	Part 2.1046	
	Part 22.913(a)	
	Part 24.232(b)	
RF Output Power	Part 27.50(b)	Pass
	Part 27.50(c)	F 855
	Part 27.50(d)	
	Part 27.50(h)	
	Part 90.635	
	Part 2.1046	
Book To Average Ratio	Part 22.913(d)	Pass
Peak-To-Average Ratio	Part 24.232 (d)	r doo
	Part 27.50(d)	
Modulation Characteristics	Part 2.1047	N/A
	Part 2.1049	
00% & 26 dB Occurring Bondwidth	Part 22.917	Deep
99% & -26 dB Occupied Bandwidth	Part 24.238	Pass
	Part 27.53(a)	
	Part 2.1051	
	Part 22.917	
	Part 24.238	
Spurious Emissions at Antenna Terminal	Part 27.53(c)(f)	Pass
opunous Emissions at Antenna Termina	Part 27.53(g)	1 835
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1053	
	Part 22.917	
	Part 24.238	
Field Strength of Spurious Radiation	Part 27.53(c)(f)	Pass
	Part 27.53(g)	
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	



	Part 2.1051	
	Part 22.917	
	Part 24.238	
Out of band amingian Dand Edge	Part 27.53(c)(f)	Deee
Out of band emission, Band Edge	Part 27.53(g)	Pass
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1055(a)(1)(b)	
	Part 22.355	
Frequency stability vs. temperature	Part 24.235	Pass
	Part 27.54	
	Part 90.213	
	Part 2.1055(d)(1)(2)	
	Part 22.355	
Frequency stability vs. voltage	Part 24.235	Pass
	Part 27.54	
	Part 90.213	

Note: 1. Pass: The EUT complies with the essential requirements in the standard.

2. The conclusion of this test report is judged by actual test data without considering measurement uncertainty.



2 GENERAL INFORMATION

2.1 GENERAL DESCRIPTION OF EUT

Description of Device (E	EUT	
EUT Name	:	
Model No.	:	S118, V31, V31 GT, S110, S110 GT, V31 Plus, V31 Ultra, S118 Pro, S118 S, S118 E, S118 SE, S118 Plus, S118 Max, S118 Ultra
DIFF.	:	There is no difference except the name of the model. All tests are made with
		the S118 model.
Power supply	:	DC 3.85V from battery or DC 11V from adapter
Support Bands	•	LTE Band 2/4/5/7/19/25/26/38//41/66
Channel Bandwidth	:	LTE Band 2: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 4: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 5: 1.4MHz, 3MHz, 5MHz, 10MHz LTE Band 7: 5MHz, 10MHz, 15MHz LTE Band 19: 5MHz, 10MHz, 15MHz LTE Band 25: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 26: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz LTE Band 38: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 38: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 41: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 5: 824 ~ 849 MHz LTE Band 5: 824 ~ 849 MHz LTE Band 7: 2500 ~2570 MHz LTE Band 19: 830 ~845MHz LTE Band 25: 1850 MHz ~ 1915 MHz LTE Band 26: 814 MHz ~ 849 MHz LTE Band 38: 2570 MHz ~ 2620 MHz
Modulation type	:	LTE Band 41: 2535MHz ~ 2655MHz LTE Band 66: 1710 MHz ~ 1780 MHz QPSK, 16QAM
Antenna Type	:	PIFA antenna, LTE Band 2: Maximum Gain is 1.8dBi. LTE Band 4: Maximum Gain is 1dBi. LTE Band 5: Maximum Gain is -2.7dBi. LTE Band 7: Maximum Gain is 0.4Bi. LTE Band 19: Maximum Gain is -2.7dBi. LTE Band 25: Maximum Gain is -2.7dBi. LTE Band 26: Maximum Gain is 0.4dBi. LTE Band 38: Maximum Gain is 0.4dBi. LTE Band 41: Maximum Gain is 0.4Bi. LTE Band 66: Maximum Gain is 1dBi. Antenna information is provided by applicant. There is WWAN diversity antenna inside the product, which is only for receiving function.
Software version	:	DOOGEE-S118-EEA-Android14.0-20240427
Hardware version	:	M116-MUB-V1
Remark 1: The worst-ca	ase s	simultaneous transmission configuration was evaluated with no non-compliance
found. Results in this re	port	are only for 4G function, and there is no other transmitter involved.
2: The LTE Band	l41 ι	upports frequency is 2535-2655MHz,Due to actual customer needs
Using software, the prot	totyp	be can only operate at 2535-2655 MHZ, other frequencies have been blocked



2.2 RELATED SUBMITTAL(S) / GRANT (S)

This submittal(s) (test report) is filing to comply with Section Part 22 subpart H and Part 24 subpart E of the FCC CFR 47 Rules.

2.3 TEST FACILITY

Company:	Beijing TIRT Technology Service Co.,Ltd Shenzhen
Address:	104 Building C, Xinmingsheng Industrial Park No.132, Zhangge Old Village East Zone, Zhangge Community, Fucheng Street, Longhua District, Shenzhen, Guangdong, P. R. China
CNAS Registration Number:	CNAS L14158
A2LA Registration Number:	6049.01
FCC Accredited Lab.Designation Number:	CN1366
FCC Test Firm Registration Number:	820690
Telephone:	+86-0755-27087573

2.4 ACCESSORIES OF DEVICE (EUT)

Accessories	Adapter	
Manufacturer	/	
Model	TP303C-US	
	Input: AC100-240V~ 50/60Hz 0.7A Max	
	Output: USB-C: 5.0V-3.0A 15.0W; 9.0V-3.0A 27.0W;	
Ratings	12.0V=2.5A 30.0W; 15.0V=2.0A 30.0W,	
Raingo	20.0V-1.5A 30.0W	
	PPS: 5.0V-11.0V=3.0A 33.0W	
	Power: 33.0W	

2.5 TESTED SUPPORTING SYSTEM DETAILS

No.	Description	Manufacturer	Model	Serial Number	Certification or SDoC
1	N/A	N/A	N/A	N/A	N/A

2.6 TEST CONDITIONS

Items	Required	Actual
Temperature range:	15-35°C	24°C
Humidity range:	25-75%	56%
Pressure range:	86-106kPa	98kPa



2.7 MEASUREMENT UNCERTAINTY

Uncertai	nty
Parameter	Uncertainty
Occupied Channel Bandwidth	±142.12 KHz
RF power conducted	±0.74 dB
RF power radiated	±3.25dB
Spurious emissions, conducted	±1.78dB
Spurious emissions, radiated (9KHz~30MHz)	±2.56dB
Spurious emissions, radiated (30MHz \sim 1GHz)	±4.6dB
Spurious emissions, radiated (Above 1GHz)	±4.9dB
Conduction Emissions(150kHz~30MHz)	±3.1 dB
Humidity	±4.6%
Temperature	±0.7°C
Time	±1.25%



3 TEST INSTRUMENTS LIST

Name of Equipment Manufacturer Model Number Serial Number Calibration Oction					
	Manufacturer			Calibration	Calibration
EMI Receiver	Rohde&Schwarz	ESIB 40	YH-TIRT-SAC-966 -20220911	2024/01/05	2025/01/04
Integral Antenna	Schwarzbeck	VULB 9163	01314	2022.12.11	2024.12.10
Integral Antenna	Rohde&Schwarz	HF907	RSM2991424	2022.12.11	2024.12.10
Preamplifier	Emtrace	RP01A	'02017	2024/01/05	2025/01/04
Preamplifier	Schwarzbeck	BBV9744	00143	2024/01/05	2025/01/04
Loop Antenna	ZHINAN	ZN30900A	12024	2024/01/05	2025/01/04
Exposure Level Tester	narda	ELT-400	N-0925	2024/01/05	2025/01/04
Horn Antenna	Schwarzbeck	BBHA9170	00956	2024/01/05	2025/01/04
RF Cable	/	LMR400UF-NMNM-7. 0M	/	2024/01/05	2025/01/04
RF Cable	/	SFT2050PUR-NMNM -7.0M	/	2024/01/05	2025/01/04
EMI Receiver	Rohde&Schwarz	ESR7	1316.3003K07-10 2611-mk	2023/11/02	2024/11/01
LISN	Rohde&Schwarz	ENV216	3560.655.12-1029 15-Bp	2023/11/02	2024/11/01
ISN	Schwarzbeck	ENY81	1309.8510.03	2024/01/05	2025/01/04
ISN	Schwarzbeck	ENY81-CAT6	1309.8526.03-101 976-kh	2024/01/05	2025/01/04
RF Cable	١	SFT2050PUR-NMNM -2.0M	\	2024/01/05	2025/01/04
CMW500	ROHDE&SCHWARZ	CMW500	120434	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSU26	200732	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSV40-N	101722	2024/01/05	2025/01/04
vector Signal Generator	KEYSIGHT	N5182B	MY56200458	2024/01/05	2025/01/04
vector Signal Generator	HEWLETT PACKARD	83752A	3610A02458	2024/01/05	2025/01/04
Filter	HEWLETT PACKARD	JS0806-F	19K8060209	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8821C	SN6262170409	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8000A	SN6262166782	2024/01/05	2025/01/04



Hubei world for communication Co., LTD SW-700/2700XP-4 /	/	/	

4 SYSTEM TEST CONFIGURATION

4.1 TEST MODE

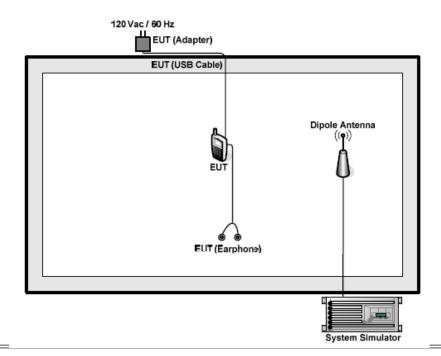
During all testing, EUT is in link mode with base station emulator at maximum power level. The spurious emission measurements were carried out in semi-anechoic chamber with 3-meter test range, and EUT is rotated on three test planes to find out the worst emission.

Test modes				
Band	Radiated	Conducted		
LTE Band 2	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 4	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 5	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 7	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 19	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 25	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 26	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 38	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 41	QPSK link, 16QAM link	QPSK link, 16QAM link		
LTE Band 66	QPSK link, 16QAM link	QPSK link, 16QAM link		

Note: Antenna port conducted and radiated test items were performed according to KDB 971168 D01 Power Meas License Digital Systems v03r1 with maximum output power.

Radiated measurements were performed with rotating EUT in different three orthogonal test planes to find the maximum emission.

4.2 CONFIGURATION OF TESTED SYSTEM





Test Requirement:	Part 2.1046,Part 22.913(a), Part 24.232(c), Part 27.50(b), Part 27.50(c), Part 27.50(d), Part 27.50(h), Part 90.635	
Test Method:	ANSI C63.26:2015	
Limit:	LTE Band 2: 2W	
	LTE Band 4: 1W	
	LTE Band 5/19: 7W	
	LTE Band 7: 2W	
	LTE Band 25: 2W	
	LTE Band 26: 100W	
	LTE Band 38: 2W	
	LTE Band 41: 2W	
	LTE Band 66: 1W	
Test setup:	EUT Splitter Tester	
	Power meter	
	Note: Measurement setup for testing on Antenna connector	
Test Procedure:	1. The transmitter output port was connected to base station.	
	2. The RF output of EUT was connected to the power meter by RF	
	cable and attenuator, the path loss was compensated to the resu	
	for each measurement.	
	3. Set EUT at maximum power through base station.	
	4. Select lowest, middle, and highest channels for each band and different modulation.	
	5. Measure the maximum burst average power.	
Toot Instrumenter	Refer to section 3 for details	
Test Instruments:	Refer to section 4.1 for details	
Test mode:		

Note: Please refer to Appendix A of the Appendix Test Data.



Test Requirement:	Part 22.913(d), FCC part24.232(d) and FCC part27.50(d)(5)	
Test Method:	ANSI C63.26:2015	
Test Limit:	Used complementary cumulative distribution function (CCDF) of analyzer to determine that PAPR will not exceed 13 dB for more than 0.1 percent of the time	
Test setup:	EUT Splitter Communication Tester SPA SPA	
	Note: Measurement setup for testing on Antenna connector	
Test Procedure:	 The testing follows FCC KDB 971168 D01 v03r01 Section 5.7 The EUT was connected to spectrum and system simulator via a power divider Using the CCDF measurement ofspectrum analyzer; Set RBW≥OBW or specified reference bandwidth; Set the number of counts to a value that stabilizes the measured CCDF curve; Set the measurement interval as 1ms Record the maximum PAPR level associated with a probability of 0.1%. 	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	

Note: Please refer to Appendix B of the Appendix Test Data.



Test Requirement:	FCC part22.913(a), FCC part24.232(b) and FCC part27.53(a), FCC part 90.209	
Test Method:	ANSI C63.26:2015	
Test setup:	EUT Splitter Communication Tester	
	Note: Measurement setup for testing on Antenna connector	
Test Procedure:	 1.The EUT's output RF connector was connected with a short cable to the spectrum analyzer, set center frequency to channel center frequency. 2.RBW was set to about 1%-5% of emission OBW, VBW≥ 3 X RBW. 3.Set spectrum analyzer detection mode to peak, and the trace mode max hold. 	
	4. Use the 99% OBW function, The 99% power OBW can be found on the plot, determine the "-26dB amplitude" as equal to reference value -26dB.	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	



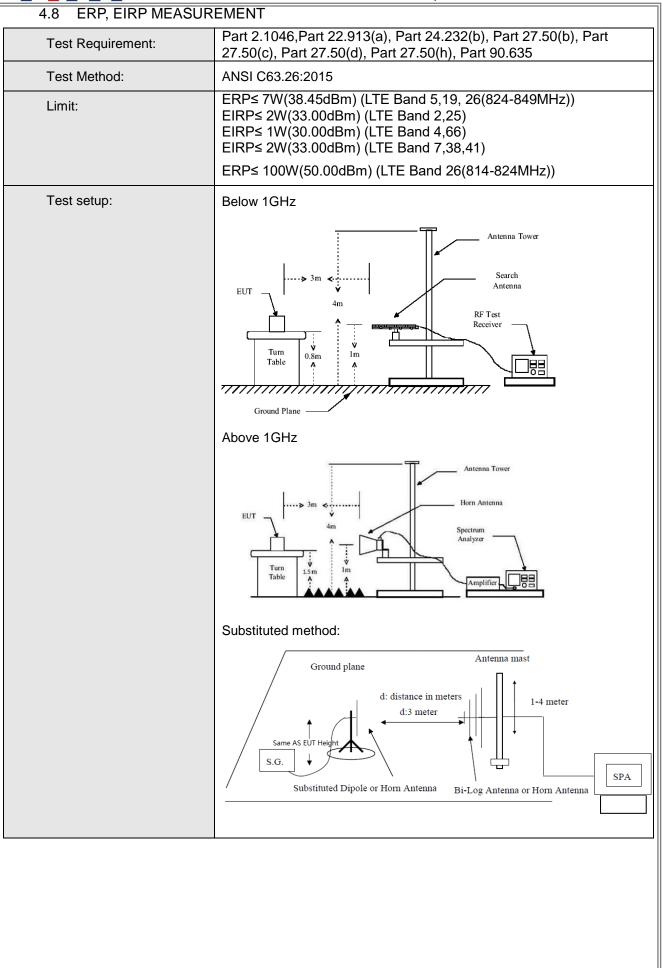
4.6 MODULATION CHARACTERISTIC

According to FCC § 2.1047(d), Part 24E & Part 27 there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.



E E E Report No.:ITEZA2-202400192RF7		
4.7 OUT OF BAND EMISSION AT ANTENNA TERMINALS		
Test Requirement:	Part 2.1051 Part 22.917 Part 24.238 Part 27.53(c)(f) Part 27.53(g) Part 27.53(h) Part 27.53(m) Part 90.691	
Test Method:	ANSI C63.26:2015	
Limit:	 ≤ -13dBm(LTE Band5,19, 26(824-849MHz)) ≤ -13dBm(LTE Band2,25) ≤ -13dBm(LTE Band12, 17, 71) ≤ -13dBm(LTE Band4,66) ≤ -25dBm(LTE Band 7, 38, 41) ≤ -13dBm(LTE Band26(814-824MHz)) 	
Test setup:	EUT Splitter Communication Tester Filter SPA	
	Note: Measurement setup for testing on Antenna connector	
Test Procedure:	 Note: Measurement setup for testing on Antenna connector The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 1MHz, sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=1MHz, VBW = 3MHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outsi and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out band Emissions. 	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	
	x D of the Appendix Test Data.	







Test Procedure:	1. The EUT was placed on an non-conductive turntable using a
	non-conductive support. The radiated emission at the fundamental
	frequency was measured at 3 m with a test antenna and EMI
	spectrum analyzer.
	2. During the measurement, the EUT was communication with the
	station. The highest emission was recorded with the rotation of the
	turntable and the lowering of the test antenna from 4m to 1m. The
	reading was recorded and the field strength (E in dBuV/m) was
	calculated.
	3. ERP were measured using a substitution method. The EUT was
	replaced by dipole antenna connected, the S.G. output was
	recorded and ERP was calculated asfollows:
	ERP = S.G. output (dBm) + Antenna Gain (dBd) – Cable Loss (dB)
	4. EIRP were measured using a substitution method. The EUTwas
	replaced by or horn antenna connected, the S.G. output was
	recorded and EIRP was calculated asfollows:
	EIRP = S.G. output (dBm) + Antenna Gain (dBi) – Cable Loss (dB)
Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass
Remark:	H,E1,E2 mean for EUT polarization of X, Y, Z
Note: Please refer to Appendix	A of the Appendix Test Data.



Report No.:ITEZA2-202400192RF7		
4.9 FIELD STRENGTH (OF SPURIOUS RADIATION MEASUREMENT	
Test Requirement:	Part 2.1053	
	Part 22.917	
	Part 24.238	
	Part 27.53(c)(f)	
	Part 27.53(g)	
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
Test Method:	ANSI C63.26:2015	
Limit:	≤ -13dBm(LTE Band 5, 19, 26(824-849MHz))	
	≤ -13dBm(LTE Band 2,25)	
	≤ -13dBm(LTE Band 4,66)	
	≤ -25dBm(LTE Band 7, 38, 41)	
	≤ -13dBm(LTE Band 26(814-824MHz))	
Test setup:	Below 1GHz	
	Antenna Tower EUT Hum Osm Ground Plane Above 1GHz U U Tum Ism Hum Hum Hum Hum Hum Hum Hum Hu	



Report No.:ITEZA2-202400192RF7

	Ground plane Ground plane d: distance in meters d: 3 meter Same AS EUT Height S.G. Substituted Dipole or Horn Antenna Bi-Log Antenna or Horn Antenna				
Test Procedure:	1. The EUT was placed on an non-conductive turntable using a				
	non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer.				
	 During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. 				
	 The frequency range up to tenth harmonic was investigated for each of three fundamental frequency(low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method. 				
	 4. The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB) 				
Test Instruments:	Refer to section 3 for details				
Test mode:	Refer to section 4.1 for details				
Test results:	Pass				



Measurement Data:

QPSK Mode:

Test mode:	LTE Band	2(1.4MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious	Spurious Emission Limit (dBm)		Result
	Polarization	Level (dBm)		Result
3730.00	Vertical	-31.61		
5597.78	V	-30.60		
7427.39	V	-33.30	-13.00	Pass
9281.38	V	-41.95		
11254.67	V			
3730.00	Horizontal	-35.44		
5520.25	Н	-35.11		
7403.26	Н	-40.99	-13.00	Pass
9243.84	Н	-46.36		
11231.97	Н			
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (IVITZ)	Polarization	Level (dBm)		Result
3729.99	Vertical	-30.88		
5640.25	V	-30.60	-13.00	Pass
7505.26	V	-35.38		
9481.87	V	-43.33		
11406.48	V			
3714.24	Horizontal	-35.21		
5668.95	Н	-35.17		Pass
7528.79	Н	-43.06	-13.00	
9425	Н	-43.33		
11328.07	Н			
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Highest
	Spurious	Emission	Limit (dDm)	Beault
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3831.53	Vertical	-31.61		
5742.76	V	-31.12		
7646.96	V	-36.11	-13.00	Pass
9517.33	V	-43.33		
11604.68	V			
3831.53	Horizontal	-35.15		
5742.25	Н	-35.11	-13.00	
7622.23	Н	-41.99		Pass
9576.78	Н	-45.73		
11529.77	Н			

Remark :

1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2. Remark"----" means that the emission level is too low (20dB lower than the limit) to be measured

3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	4(1.4MHz)	Test channel:	Lowest	
- (111)	Spurious Emission				
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3427.00	Vertical	-32.64			
5144.22	V	-28.01			
6869.26	V	-36.01	-13.00	Pass	
8538.00	V	-44.22			
10327.64	V				
3426.42	Horizontal	-33.9			
5126.62	Н	-43.08			
6866.83	Н	-40.76	-13.00	Pass	
8603.46	Н	-38.99			
10242.65	Н				
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle	
	Spurious	Emission	Limit (dDm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3441.23	Vertical	-31.64			
5139.78	V	-30.06		Pass	
6977.24	V	-37.40	-13.00		
8663.58	V	-43.26			
10473.44	V				
3469.25	Horizontal	-35.25			
5114.26	Н	-42.22			
6961.89	Н	-41.01	-13.00	Pass	
8715.09	Н	-39.93			
10317.46	Н				
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
Frequency (IVITIZ)	Polarization	Level (dBm)		Result	
3514.13	Vertical	-31.12			
5221.91	V	-28.06			
7029.38	V	-34.44	-13.00	Pass	
8767.27	V	-43.49			
10664.54	V				
3542.66	Horizontal	-34.85			
5247.16	Н	-42.02	-13.00		
7057.05	Н	-40.30		Pass	
8821.13	Н	-41.68			
10545.15	Н				
Pomark.					

1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured

3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	5(1.4MHz)	Test channel:	Lowest	
	Spurious Emission		Limit (dDm)	Decult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1613.40	Vertical	-32.88			
2444.40	V	-32.24			
3221.92	V	-35.91	-13.00	Pass	
4140.51	V	-43.33			
5071.37	V				
1809.38	Horizontal	-33.95			
2499.68	Н	-43.28			
3882.36	Н	-39.47	-13.00	Pass	
4310.82	Н	-37.94			
5145.78	Н				
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
Frequency (MHZ)	Polarization	Level (dBm)		Result	
1637.00	Vertical	-31.63			
2420.76	V	-29.04		Pass	
3249.30	V	-35.07	-13.00		
4284.51	V	-43.42			
5157.63	V				
4747.68	Horizontal	-34.10			
2662.69	Н	-41.63			
3853.48	Н	-39.82	-13.00	Pass	
4424.08	Н	-40.19			
5145.78	Н				
Test mode:		5(1.4MHz)	Test channel:	Highest	
Frequency (MHz)	•	Emission	Limit (dBm)	Result	
	Polarization	Level (dBm)		Rooun	
1701.97	Vertical	-34.64	_		
2559.85	V	-32.04	_		
3417.72	V	-35.00	-13.00	Pass	
4366.57	V	-43.33			
5258.10	V				
1749.38	Horizontal	-34.95			
2871.62	Н	-42.29	-13.00		
3437.39	Н	-41.35		Pass	
4393.39	Н	-40.85			
5145.76	Н				

1. The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	d 7(5MHz)	Test channel:	Lowest
	Spurious	Emission	Limit (dDm)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5227.70	Vertical	-31.53		
4859.89	V	-28.75		
10092.39	V	-35.26	-25.00	Pass
13590.87	V	-43.95		
15231.63	V			
5136.15	Horizontal	-34.05		
7940.85	Н	-42.14		
10152.33	Н	-39.63	-25.00	Pass
12811.02	Н	-40.67		
15135.76	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dDm)	Decult
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result
5156.40	Vertical	-30.48		
7639.43	V	-30.72		Pass
10222.38	V	-34.33	-25.00	
13281.99	V	-43.97		
15634.97	V			
5128.47	Horizontal	-36.50		
7734.16	Н	-42.19		
10275.62	Н	-39.26	-25.00	Pass
13876.55	Н	-37.93		
15361.25	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MITZ)	Polarization	Level (dBm)		Result
5238.90	Vertical	-33.64		
7882.82	V	-34.14		
10346.39	V	-33.97	-25.00	Pass
12920.87	V	-44.23		
15439.68	V			
5224.25	Horizontal	-34.81		
7734.42	Н	-42.06	-25.00	
10354.96	Н	-40.28		Pass
12777.08	Н	-40.80		
15361.66	Н			

1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured

3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	19(5MHz)	Test channel:	Lowest
	Spurious	Spurious Emission		Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1361.00	Vertical	-31.61		
2694.78	V	-33.75		
3348.23	V	-34.27	-13.00	Pass
4216.57	V	-41.92		
5062.60	V			
1405.02	Horizontal	-32.22		
2500.13	Н	-42.02		
3640.06	Н	-36.82	-13.00	Pass
4327.08	Н	-34.93		
5145.15	Н			
Test mode:	LTE Band	19(5MHz)	Test channel:	Middle
	Spurious	Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1535.60	Vertical	-30.38		
2647.39	V	-32.04		Pass
3447.93	V	-35.31	-13.00	
4318.02	V	-43.28		
5253.94	V			
4842.66	Horizontal	-32.02		Pass
2551.12	Н	-38.59		
3952.83	Н	-38.75	-13.00	
4335.01	Н	-39.24		
5362.76	Н			
Test mode:	LTE Band	19(5MHz)	Test channel:	Highest
Frequency (MHz)	•	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Koout
1525.13	Vertical	-35.65		
2317.16	V	-31.01		
3583.86	V	-35.37	-13.00	Pass
4418.00	V	-42.48		
5402.64	V			
1742.65	Horizontal	-33.19		
2863.23	Н	-41.23	-13.00	
3563.82	Н	-39.56		Pass
4410.83	Н	-39.66		
5145.15	Н			



Test mode:	LTE Band	25(5MHz)	Test channel:	Lowest	
Fraguanov (MHz)	Spurious	Emission	Limit (dBm)	Popult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (ubiii)	Result	
5133.13	Vertical	-33.12			
7636.66	V	-30.20			
10122.44	V	-37.15	-13.00	Pass	
12259.28	V	-40.29			
15328.49	V				
5046.68	Horizontal	-36.48			
7536.44	Н	-39.06			
10556.36	Н	-34.81	-13.00	Pass	
12620.46	Н	-37.53			
15239.39	Н		_		
Test mode:	LTE Band	25(5MHz)	Test channel:	Middle	
	Spurious	Emission	Limit (dBm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dbm)	Result	
5250.60	Vertical	-31.38			
7641.39	V	-28.11		Pass	
10223.86	V	-33.04	-13.00		
12539.53	V	-41.22			
15512.00	V				
5217.95	Horizontal	-30.91			
7516.72	Н	-35.08			
10263.83	Н	-38.79	-13.00	Pass	
13590.86	Н	-39.66			
15316.95	Н				
Test mode:	LTE Band	25(5MHz)	Test channel:	Highest	
Frequency (MHz)	•	Emission	Limit (dBm)	Result	
	Polarization	Level (dBm)	Linin (dbiri)	Roodit	
5210.00	Vertical	-30.38	_		
7861.89	V	-30.97	_		
10010.00	V	-32.40	-13.00	Pass	
12233.31	V	-43.33			
15502.64	V				
5304.89	Horizontal	-36.48			
7820.39	Н	-41.63	-13.00		
10401.33	Н	-39.25		Pass	
12265.33	Н	-38.10			
15324.89	Н				

1 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

- 2 Remark"----" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(814-824MHz):		Band 26(5MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious Emission		Limit (dBm)	Result
	Polarization	Level (dBm)		Result
3429.00	Vertical	-31.63		
7817.49	V	-30.75		
10128.79	V	-32.26	-13.00	Pass
12313.27	V	-43.33		
16340.88	V			
5190.89	Horizontal	-30.29		
7616.72	Н	-42.16		
10260.46	Н	-40.29	-13.00	Pass
12591.32	Н	-38.17		
15217.16	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fraguanay (MHz)	Spi	urious Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5130.00	Vertical	-29.44		
7642.29	V	-27.77	-13.00	Pass
10245.41	V	-33.81		
13276.02	V	-41.06		
15647.88	V			
5234.49	Horizontal	-31.24		
7695.83	Н	-36.13		
10282.09	Н	-39.07	-13.00	Pass
12660.12	Н	-39.21		
15266.40	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
	Spi	urious Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5226.78	Vertical	-33.48		
7825.87	V	-28.73		
10346.93	V	-36.10	-13.00	Pass
12865.98	V	-41.34		
15442.21	V			
5140.81	Horizontal	-34.30		
7819.96	Н	-40.86	-13.00	
10341.05	Н	-38.15		Pass
12996.09	Н	-39.49]	
15268.39	Н			

1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured

3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
_	Spi	urious Emission		
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3913.97	Vertical	-32.44		
5701.95	V	-28.06		
10249.26	V	-32.99	-13.00	Pass
12291.87	V	-43.33		
13524.41	V			
3843.25	Horizontal	-36.80		
7263.42	Н	-39.86		
10303.96	Н	-39.59	-13.00	Pass
12121.06	Н	-40.66		
13341.22	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
	Spi	urious Emission	Limit (dDm)	Deput
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3690.51	Vertical	-32.25		
7908.77	V	-28.04		Pass
10448.93	V	-32.97	-13.00	
12030.08	V	-42.89		
15885.94	V			
3842.99	Horizontal	-33.96		
7580.13	Н	-42.03		
10484.22	Н	-38.66	-13.00	Pass
12532.39	Н	-39.78		
15334.26	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
	Spi	urious Emission	Line it (dDne)	Decult
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3864.60	Vertical	-29.32		
7829.66	V	-25.00		
10449.26	V	-35.14	-13.00	Pass
12338.00	V	-43.33		
15615.61	V			
3901.65	Horizontal	-32.06		
7834.16	Н	-39.09	-13.00	
10454.89	Н	-39.59		Pass
12382.66	Н	-40.77		
15285.49	Н			

1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured

3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode		Band 38(5MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious Emission		Limit (dBm)	Result
· · · · · ·	Polarization	Level (dBm)	Einin (dBin)	Result
2627.51	Vertical	-31.59		
5254.65	V	-30.83		
10562.08	V	-33.51	-25.00	Pass
12213.81	V	-43.20		
13695.28	V			
2640.28	Horizontal	-36.27		
5228.34	Н	-41.81		
10849.50	Н	-41.18	-25.00	Pass
12302.84	Н	-41.66		
13262.02	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Middle
	Spi	urious Emission	Limit (dBm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Liniit (dbin)	Result
2757.32	Vertical	-29.39		
5482.86	V	-32.49		Pass
10636.83	V	-34.00	-25.00	
12863.42	V	-45.18		
15707.42	V			
2685.28	Horizontal	-36.00		
5431.87	Н	-40.60		
10837.54	Н	-40.64	-25.00	Pass
12308.04	Н	-40.64		
15328.67	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Highest
Frequency (MHz)	Spi	urious Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	Linii (dbiii)	Result
2625.13	Vertical	-30.86		
6892.87	V	-32.12		
10436.87	V	-33.48	-25.00	Pass
12723.29	V	-43.04		
15635.79	V			
2686.88	Horizontal	-31.27		
5187.54	Н	-40.62]	
10758.43	Н	-40.64	-25.00	Pass
13305.93	Н	-41.02		
16258.29	Н			

1 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.